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EXPERIENCE

Principal Technologist, Statistician -- General Electric Global Research Center, Schenectady, NY (since 1990).

- 2007-present: *Leading research projects on protection of digital assets at NBC/Universal.*
- 2005-2006: *Led research on early detection of locomotive engine failures through embedded algorithms based on statistical modeling of parametric sensor data.*
- 2000-2005: *Responsible for projects in the area of Decision Technologies at GE Advanced Materials: Proposed, initiated, and led R&D projects in the areas of product development, quality improvement and productivity.*
- 2000: *Led on time delivery of Credit Decision and Funding projects at GE Capital Small Business Solutions.*
- 1998-2000: *Provided corporate-wide leadership to project, program and training activities in Design for Six Sigma for Business Processes. Led deployment in transactional and fulfillment processes.*
- 1990-1998: *Provided statistical guidance on key projects involving quality, reliability, and productivity improvement at GE Transportation Systems, GE Aircraft Engines, GE Medical Systems and GE Power Generation; Co-developed, published and/or patented applied research into reliability and life-testing, multivariate diagnostics, optimal control of short run processes, and identification of process change-points.*

Adjunct Professor, The Graduate College of Union University, Schenectady, NY (1990-present).

- *MBA and Graduate Level Courses Taught: Quality Management Systems, Reliability Data Analysis, Experimental Design, Sampling, Time Series Analysis, Multivariate Statistical Analysis, Linear Statistical Models, Probability and Statistics, Project Management.*

Visiting Researcher: National Institute of Standards and Technology, Gaithersburg, MD (1990-1991).

- *Co-developed and published statistical methodology (based on power-lognormal distribution) for modeling and analysis of electromigration failures in the semiconductor industry.*

PROFESSIONAL ACTIVITIES

- Elected Member, International Statistical Institute, 1997.
- Elected Fellow, American Statistical Association, 1996.
- Associate Editor, *Technometrics* and *Quality Engineering*.
- Publications: 1 book, 8 book chapters, 50+ articles and discussion papers, regular invited contributor to *Quality Progress* and *Six Sigma Forum Magazine*, numerous conference presentations.
- Book (with Gerald J. Hahn) "The Role of Statistics in Business and Industry." To be published by Wiley-Interscience, 2008.
- GE Awards: Mentor of the Year (2003), Hull Award (1995), Whitney Technical Achievement (1995, 1996, 1998), MVP GE Plastics (1994, 1998).
- 4 U.S. Patents.

EDUCATION

- Ph.D. in Administrative and Engineering Systems (Major: Applied Statistics), 1989; M.S. in Operations Research and Applied Statistics, 1987, The Graduate College of Union University, Schenectady, NY.
- M.B.A., 1985; B.Sc. (H.Hons) in Management, 1983, M.E.T.U, Ankara, Turkey.